

Notice of References Cited	Application/Control No. 10/802,162	Applicant(s)/Patent Under Reexamination LEE, HWAL RIM	
	Examiner Paulos M. Natnael	Art Unit 2622	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,236,432 B1	05-2001	Lee, Hyun-Su	375/240.26
*	B	US-7,051,359 B2	05-2006	Kim et al.	725/131
*	C	US-5,574,509 A	11-1996	Citta et al.	348/569
*	D	US-5,966,186 A	10-1999	Shigihara et al.	348/570
*	E	US-6,389,070 B1	05-2002	Cugnini et al.	375/232
*	F	US-5,940,028 A	08-1999	Iwamura, Ryuichi	342/359
*	G	US-6,985,190 B1	01-2006	Klopfenstein et al.	348/569
*	H	US-6,982,745 B2	01-2006	Miyabayashi, Naoki	348/193
*	I	US-6,236,432 B1	05-2001	Lee, Hyun-Su	375/240.25
*	J	US-5,841,472 A	11-1998	Rim et al.	375/240.25
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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